

# Nanostructured Photoelectron Emitters for Electron Beamlet Array Generation

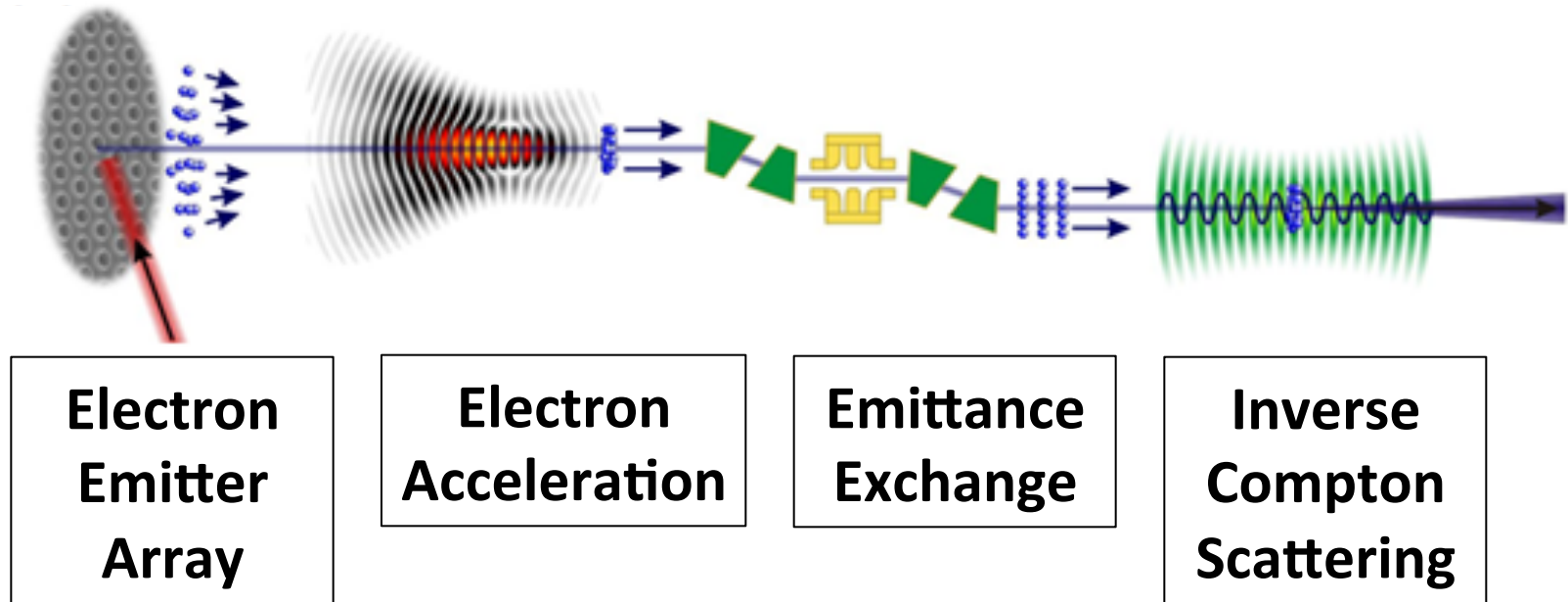
Richard Hobbs, Michael Swanwick, Phillip Keathley,  
Yujia Yang, William Graves, Karl Berggren, Luis  
Velasquez-Garcia & Franz Kaertner



**Massachusetts  
Institute of  
Technology**

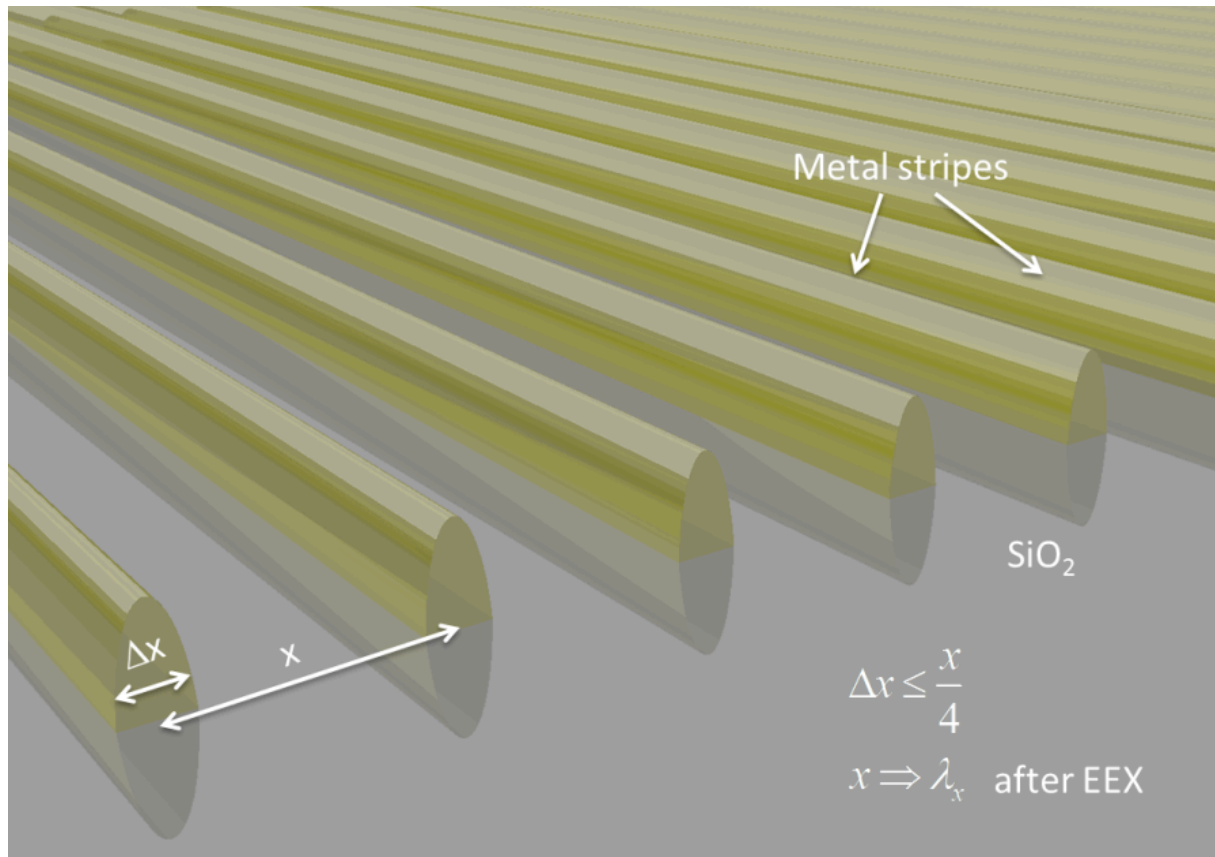
# Overview

- Why an electron beamlet array?



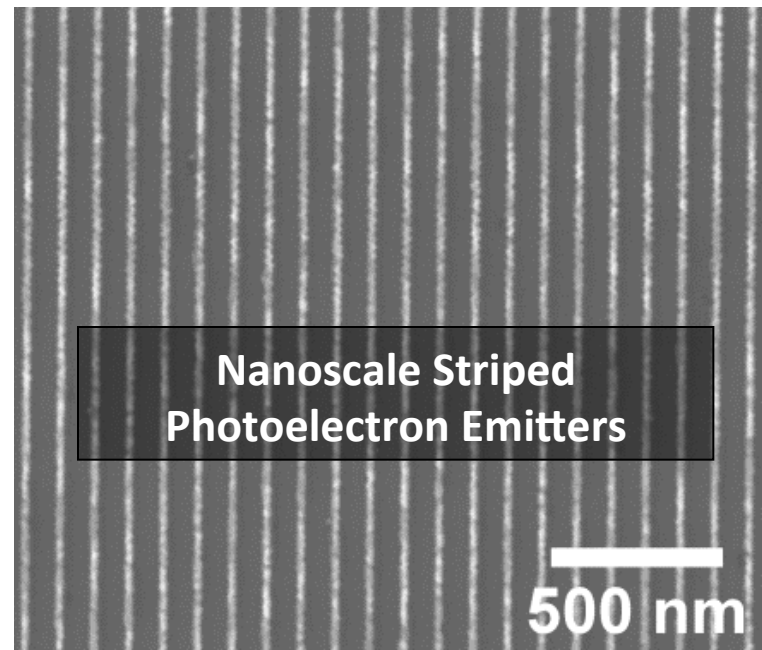
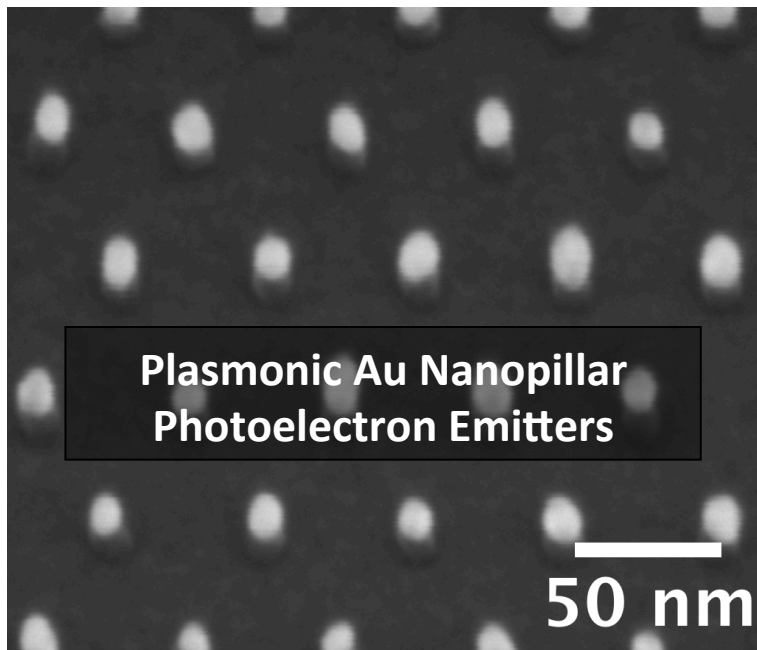
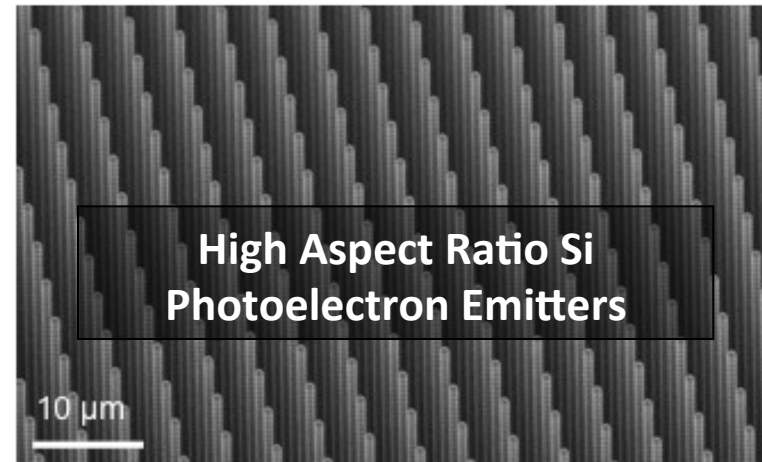
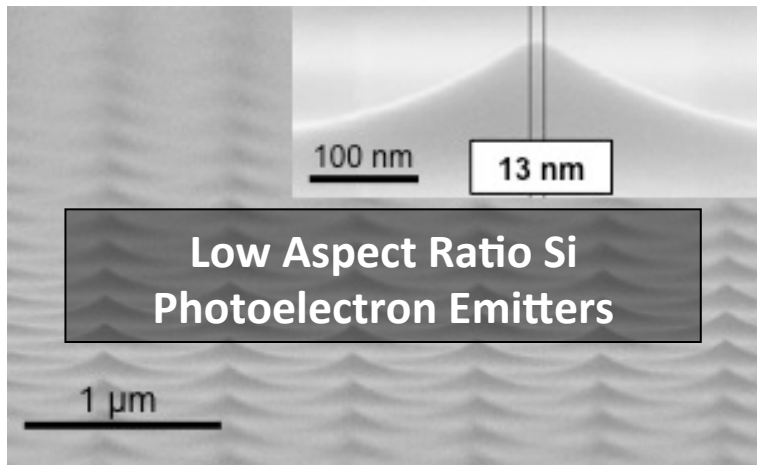
- Coherent electron bunches generate coherent x-rays via ICS

# Cathode Requirements



- Emitter pitch ( $x$ ) demagnified to  $\lambda_x$  in EEX
- Longitudinal electron bunch width  $\propto \Delta x$

# Nanostructured Cathode Materials



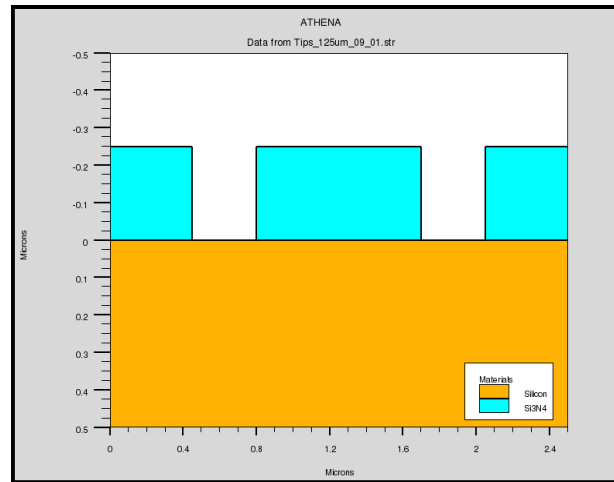
# Low Aspect Ratio Si Photoelectron Emitter Array

---

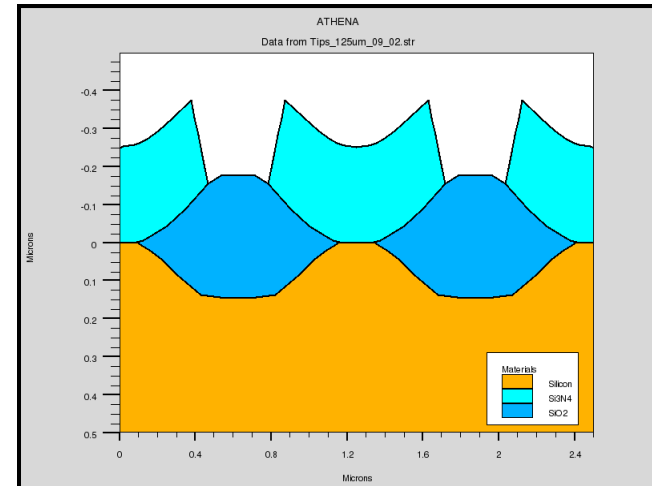
- Goals
  - Highly uniform emitter geometry over entire area of laser spot
  - Uniform charge distribution
  - ~1 pC per laser pulse
- Fabrication
  - Optical lithography and diffusion limited oxidation method
  - Emitter pitch as low as 1.25  $\mu\text{m}$
  - Highly uniform emitter radii across 150 mm wafer ( $\sigma \sim 1 \text{ nm}$ )

# Si Tip Array Fabrication

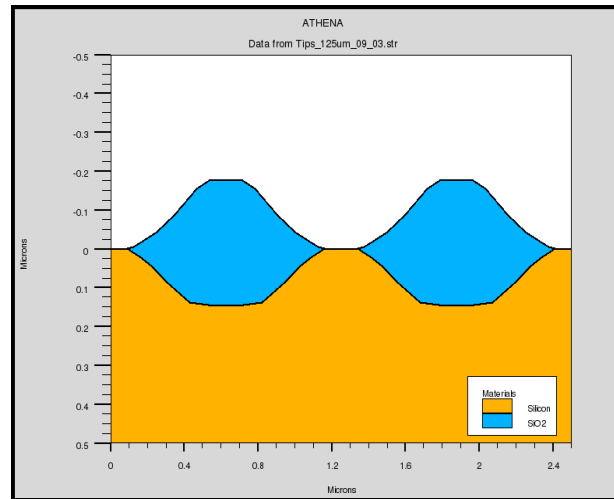
- Stress-limited oxidation
- Uniform oxide thickness across surface
- Tip radii variation limited by **spatial variation in lithography**
- Tip radii as small as 6-7 nm



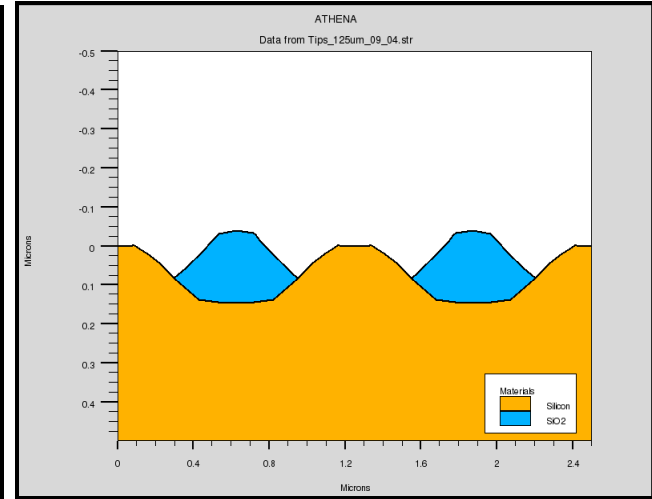
1) Define and Etch Nitride Disks



2) Oxidation of Si

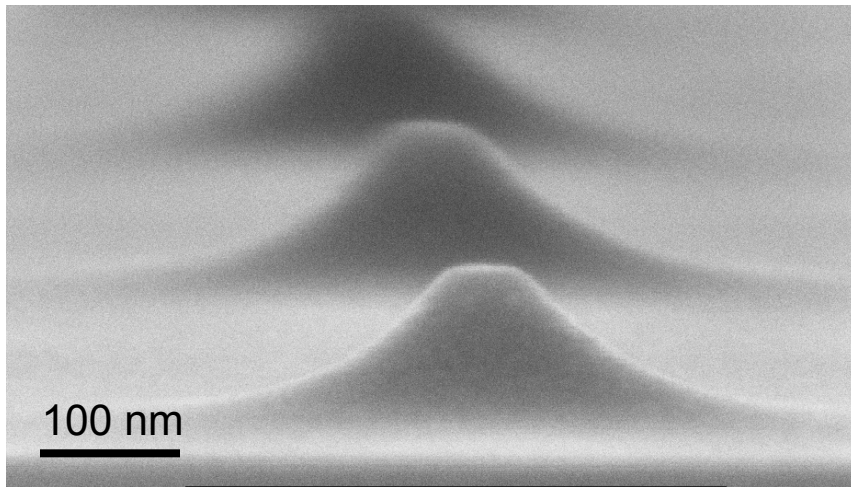


3) Removal of Nitride

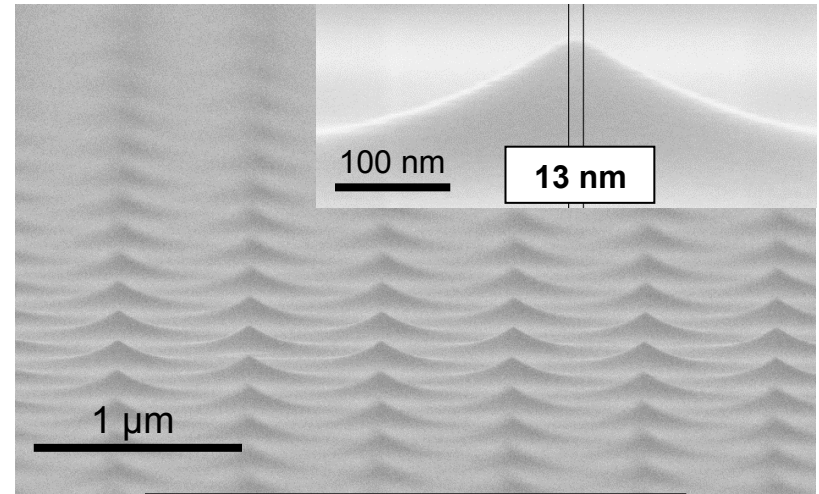


4) Etchback Oxide

# Diameter Variation – Single and Double Oxidation



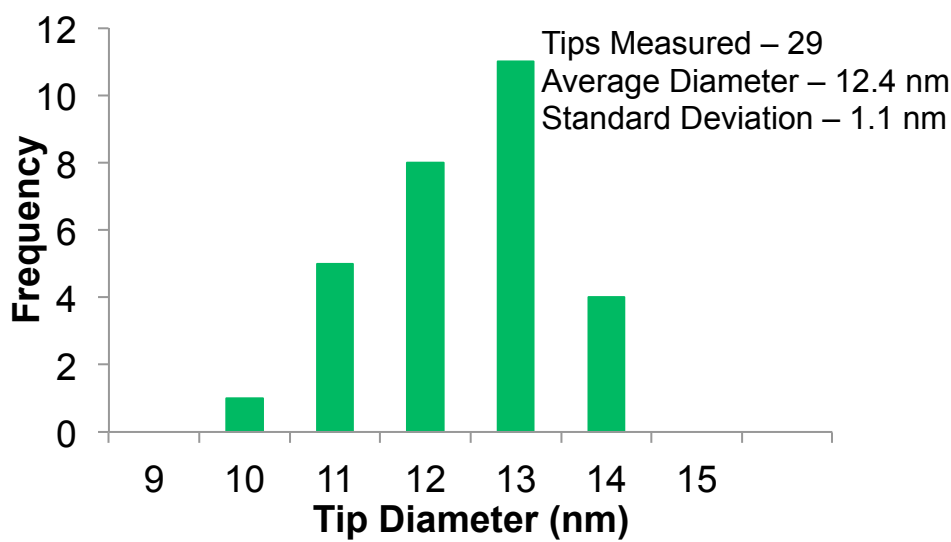
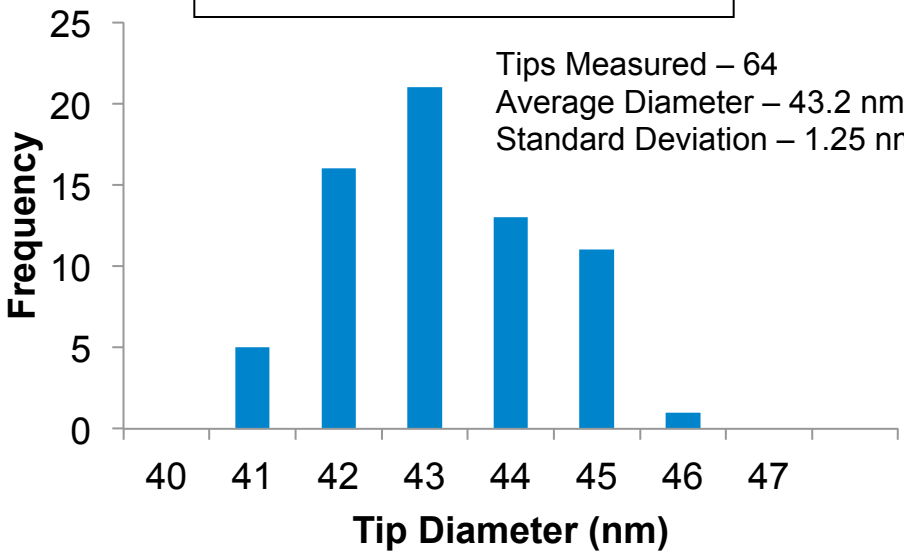
Diameter = 43.2 nm +/- 2.89%



Diameter = 12.4 nm +/- 8.87%

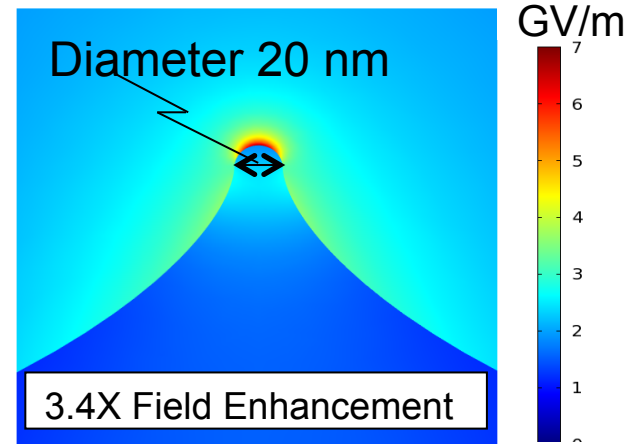
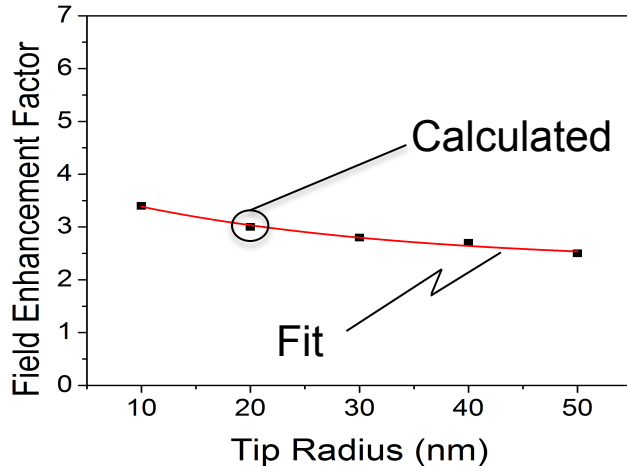
Tips Measured – 64  
Average Diameter – 43.2 nm  
Standard Deviation – 1.25 nm

Tips Measured – 29  
Average Diameter – 12.4 nm  
Standard Deviation – 1.1 nm



■ Stress-limited oxidation results in improved tip radii statistics

# Simulation of Local Field Enhancement at Si Tips



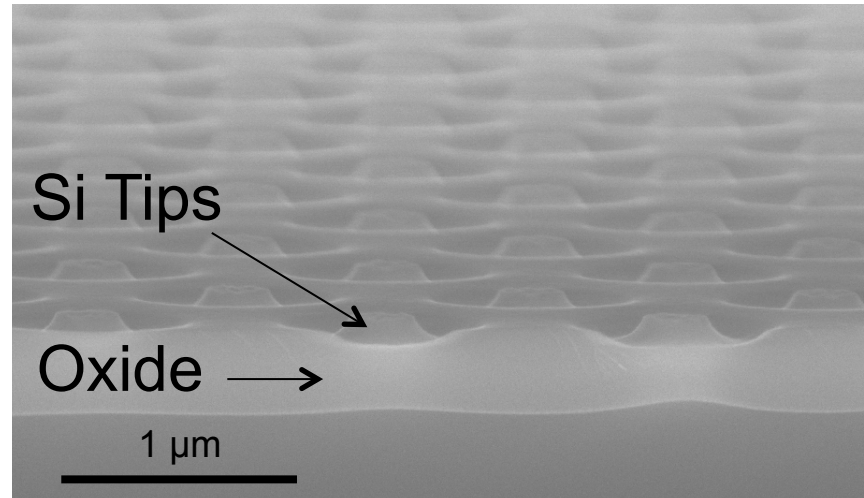
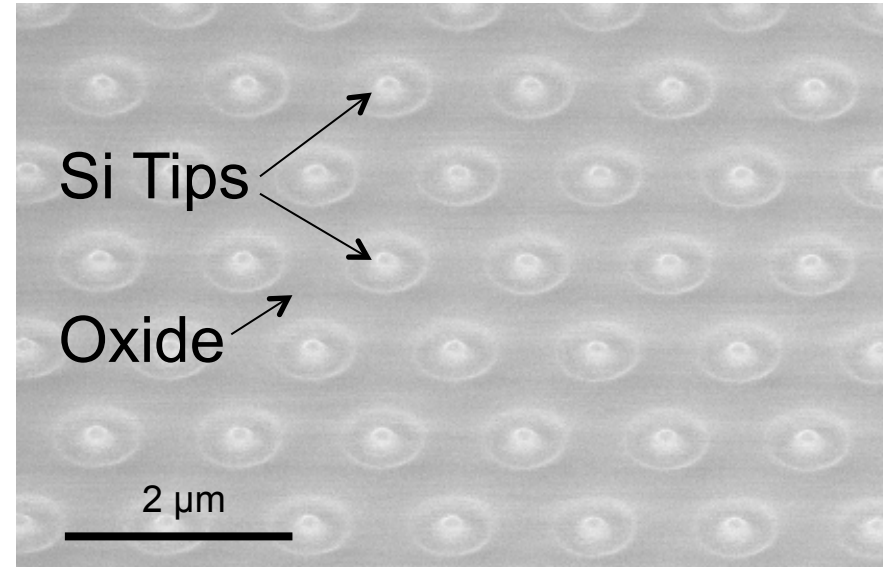
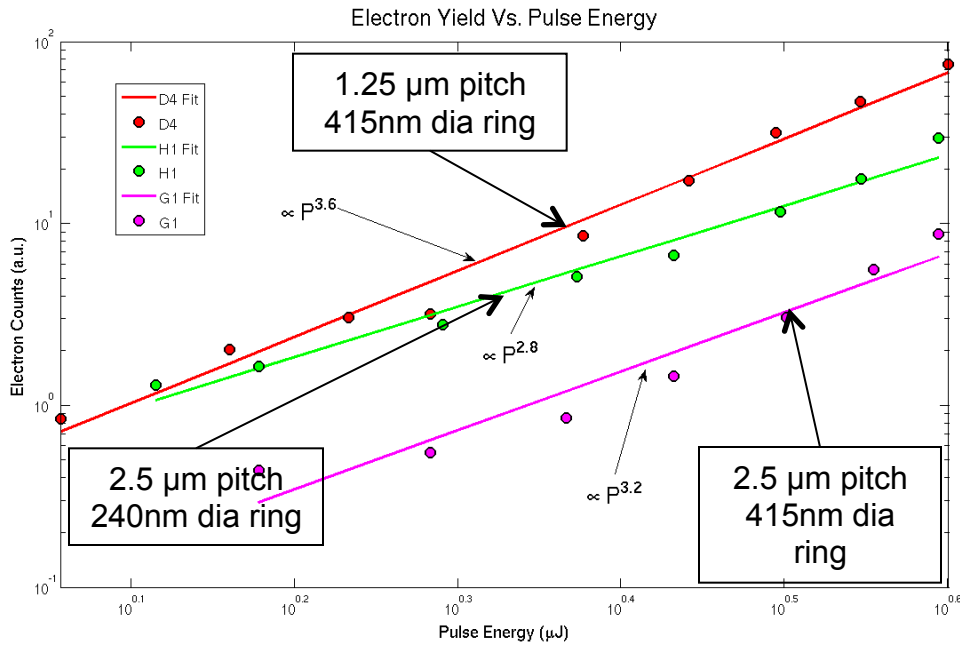
## Field Enhancement Simulations Results

- $2 \text{ GVm}^{-1}$ , p-polarized, CW, 800 nm illumination
- Pseudo-linear dependence of field enhancement on tip radius

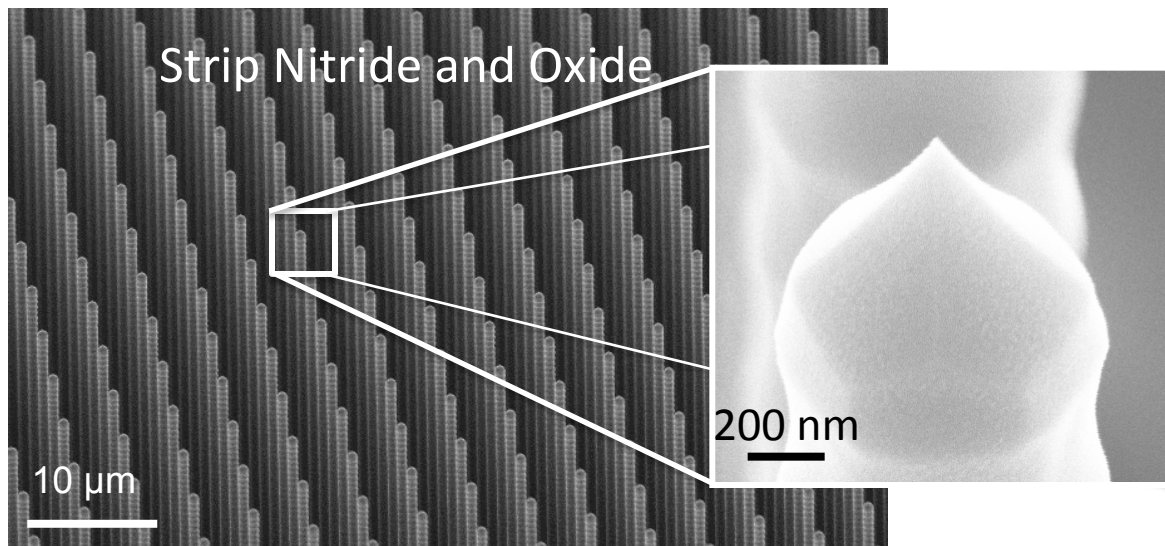
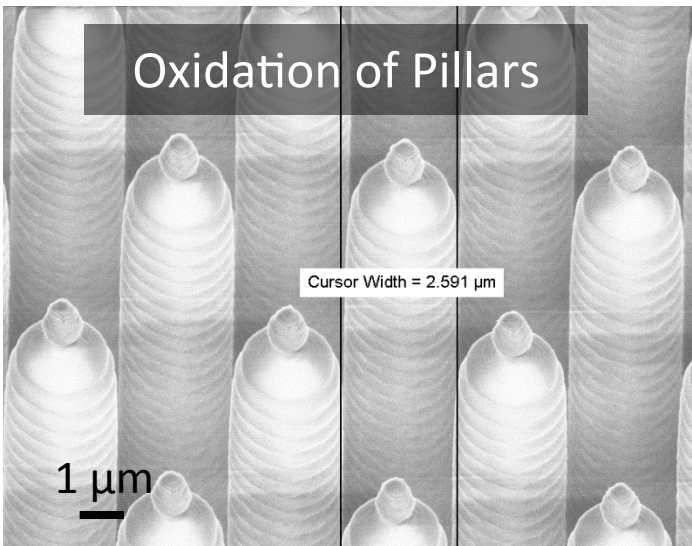
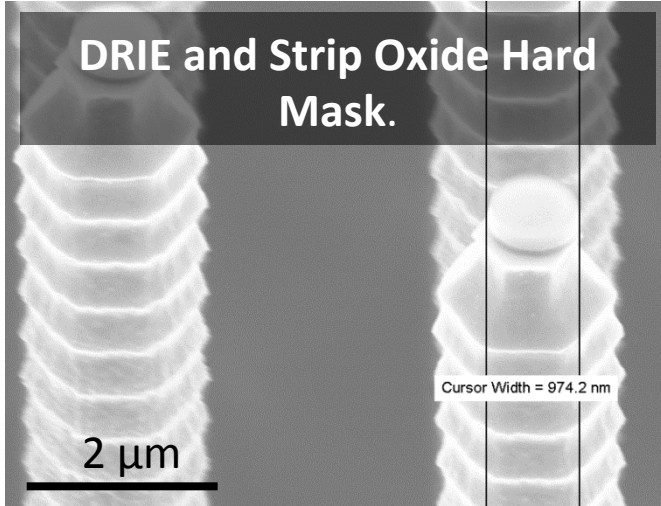
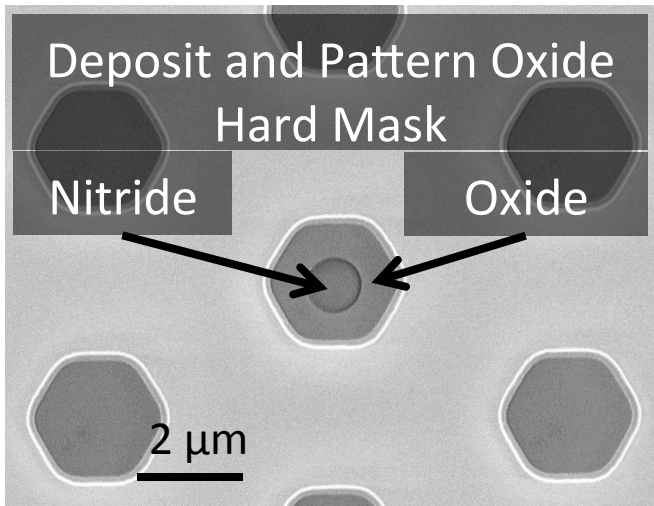
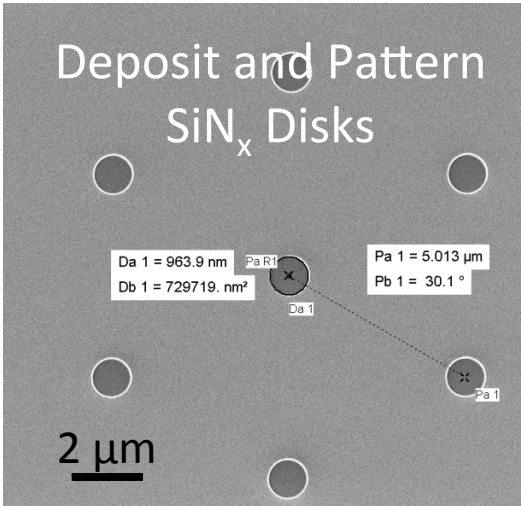
Simulations conducted by Y. Yang (Berggren Group)



# Multi-Photon Photoelectron Emission

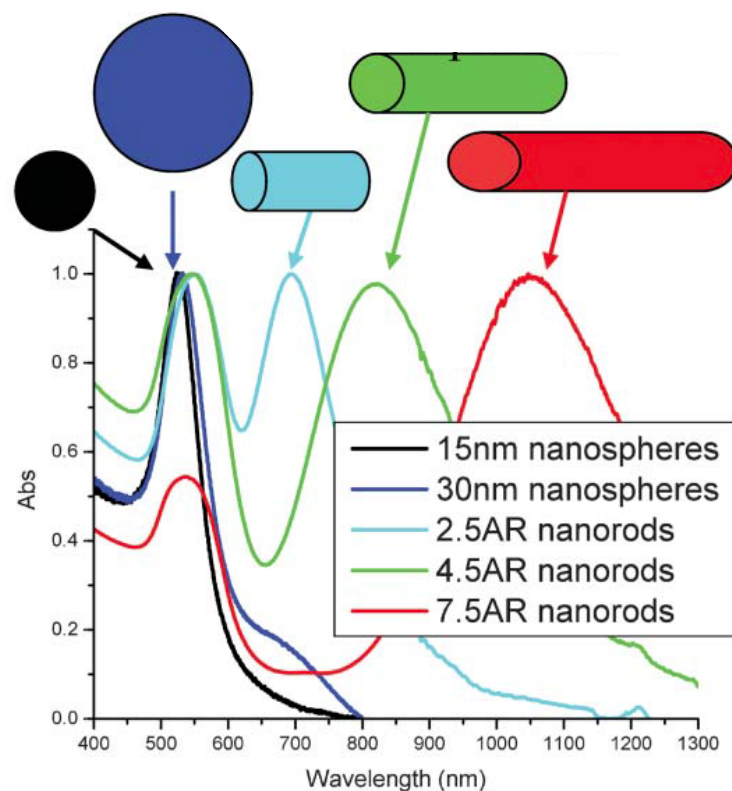


# High-Aspect Ratio Si Photoelectron Emitter Arrays



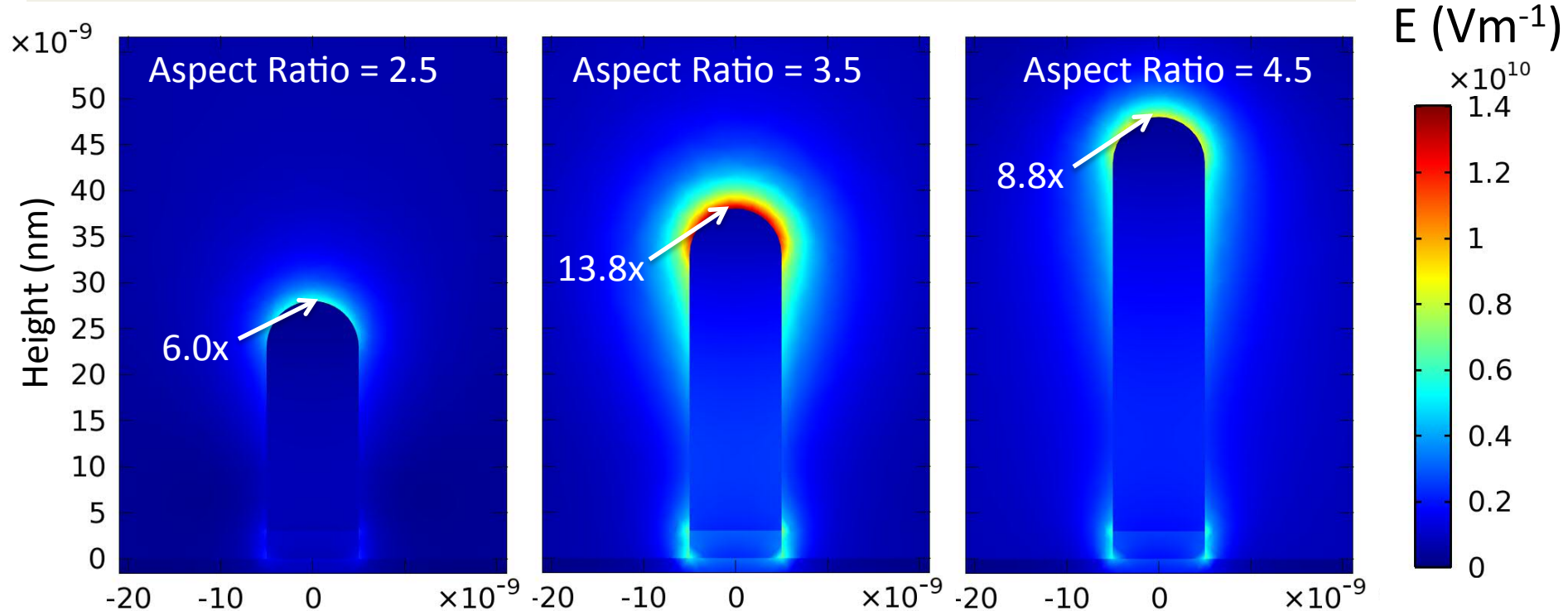
# Au Nanopillar Emitter Arrays

- Surface plasmons can strongly enhance local electric fields
- Longitudinal surface plasmon band is geometry dependent in Au
- Light source
  - Ti:Sapphire laser ( $\lambda = 800$  nm)
- Au pillar geometry tuned to produce longitudinal mode at  $\lambda = 800$  nm



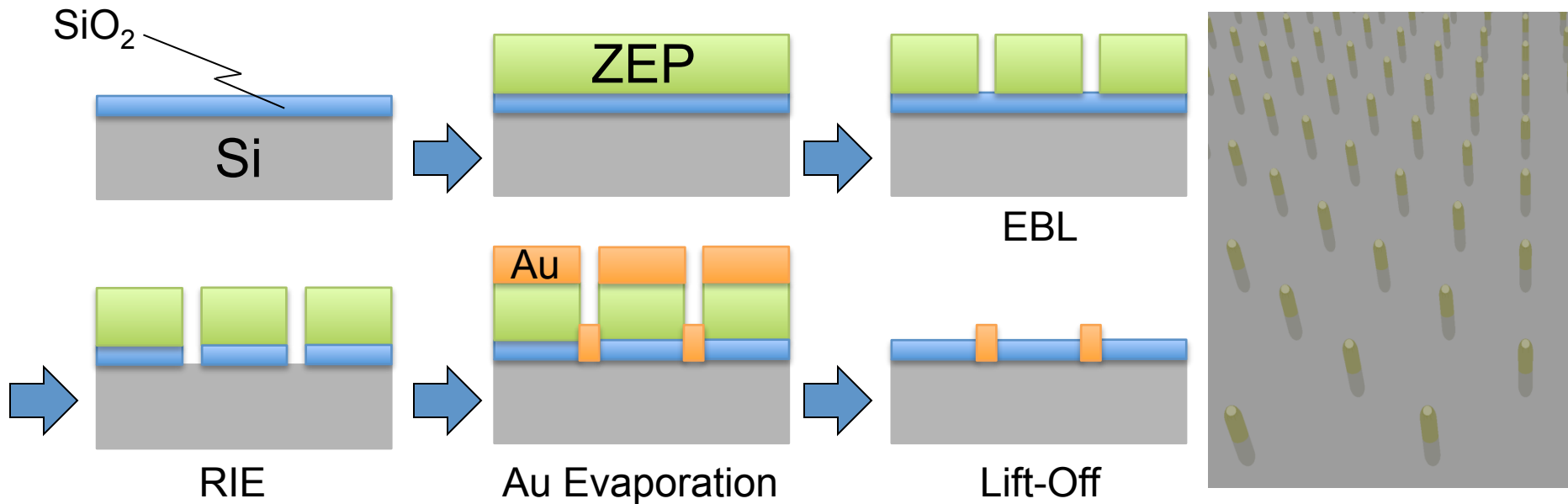
*Chem. Soc. Rev.*, 2006, 35, 209–217

# Geometry Dependence



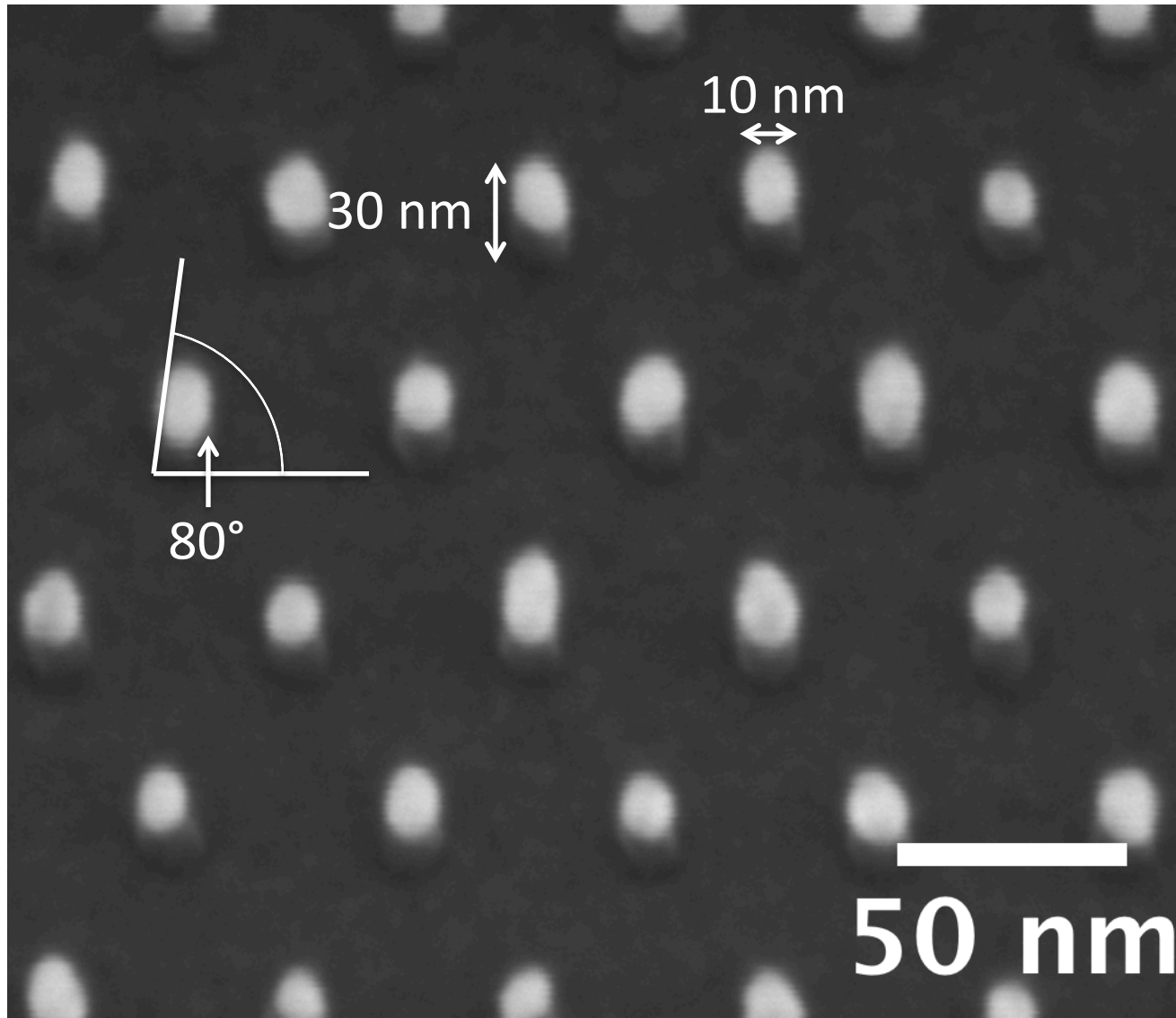
- Simulation of local electric field strength at Au nanopillars
- Coherent 800 nm p-polarized incident plane wave,  $1 \text{ GVm}^{-1}$
- Maximum field enhancement for aspect ratio of 3.5
- Au nanopillars with AR = 3.5 have peak longitudinal SP absorbance band at 800nm

# Metal Nanopillar Array Fabrication



- SiO<sub>2</sub> coating to prevent background electron emission
- ZEP resist provides higher etch resistance than PMMA
- Flexible process compatible with other metals *e.g.* Cu strip array fabrication for photocathode development

# Au Nanopillar Array Geometry



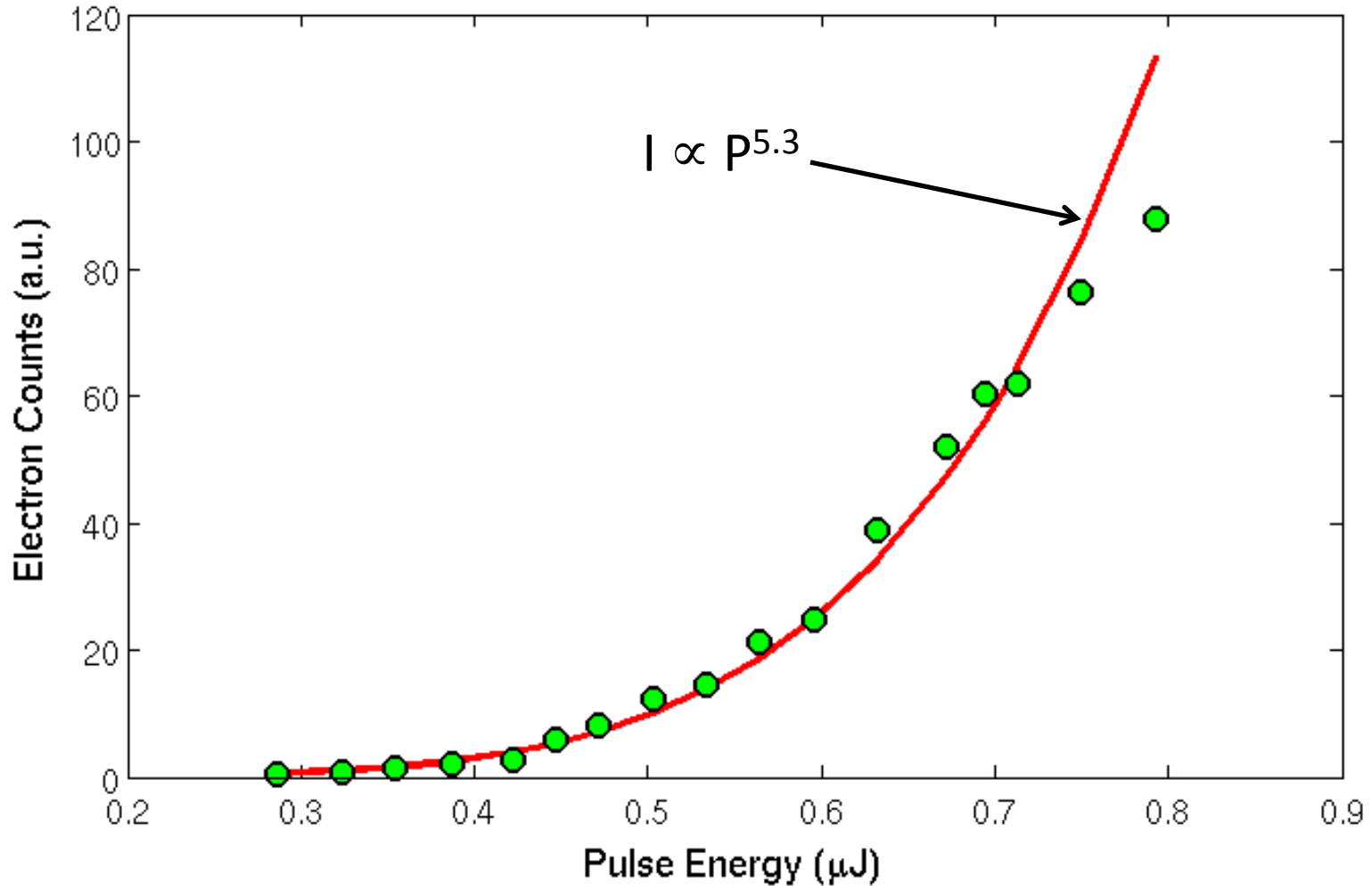
FEI Helios SEM  
resolution  
0.8-0.9 nm

Mean Au pillar  
tip diameter  
10 nm

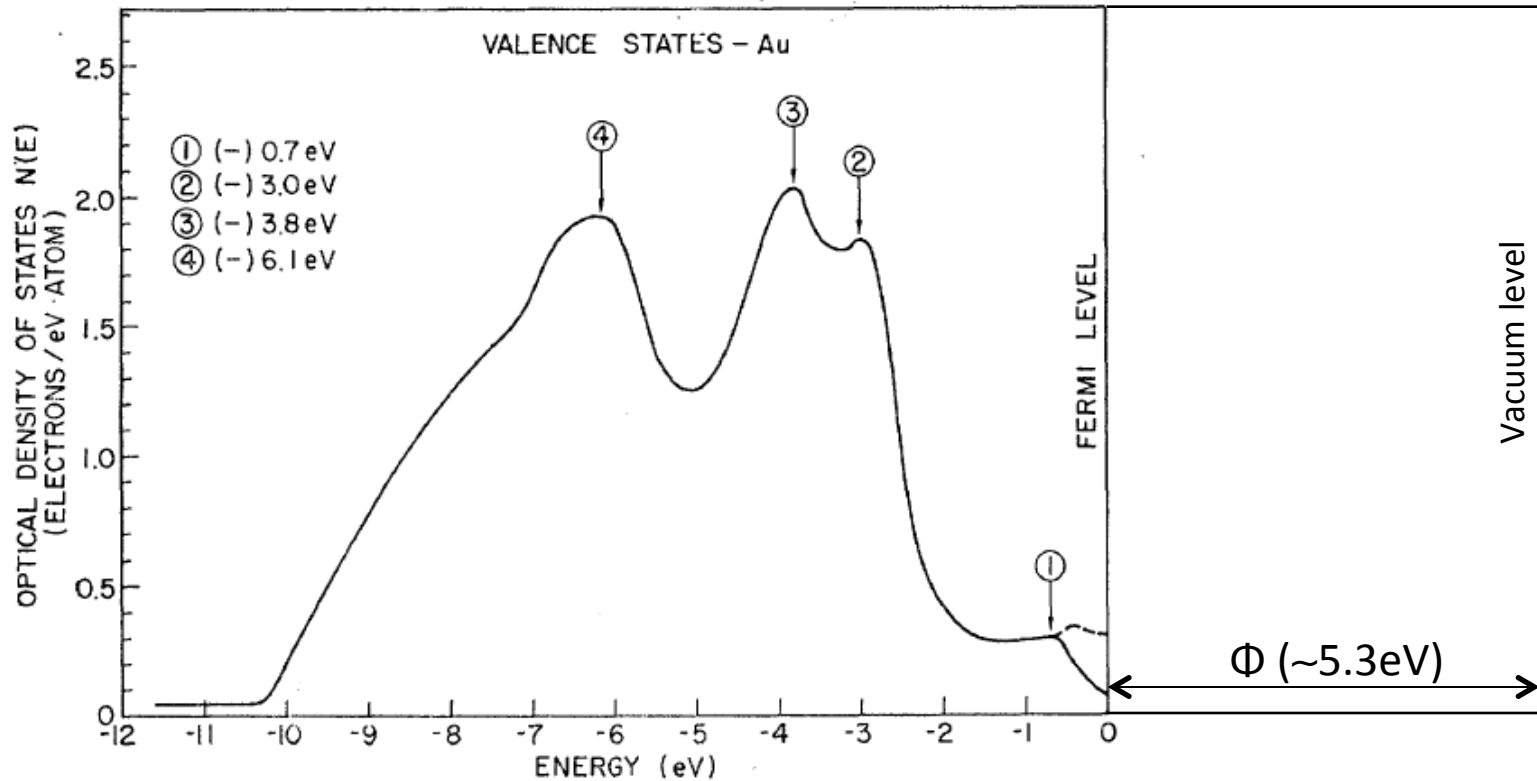
Standard  
deviation  
1 nm

# Electron Emission Spectra

Electron Yield Vs. Pulse Energy



# Au d-bands Electron Origin



- $I \propto P^{5.3}$  suggests 5-6 photon absorption (7.75-9.3 eV)
- Previously reported by Ropers *et al.*<sup>2</sup> for single tips
- Au d-bands lie 7.5-10 eV below vacuum level

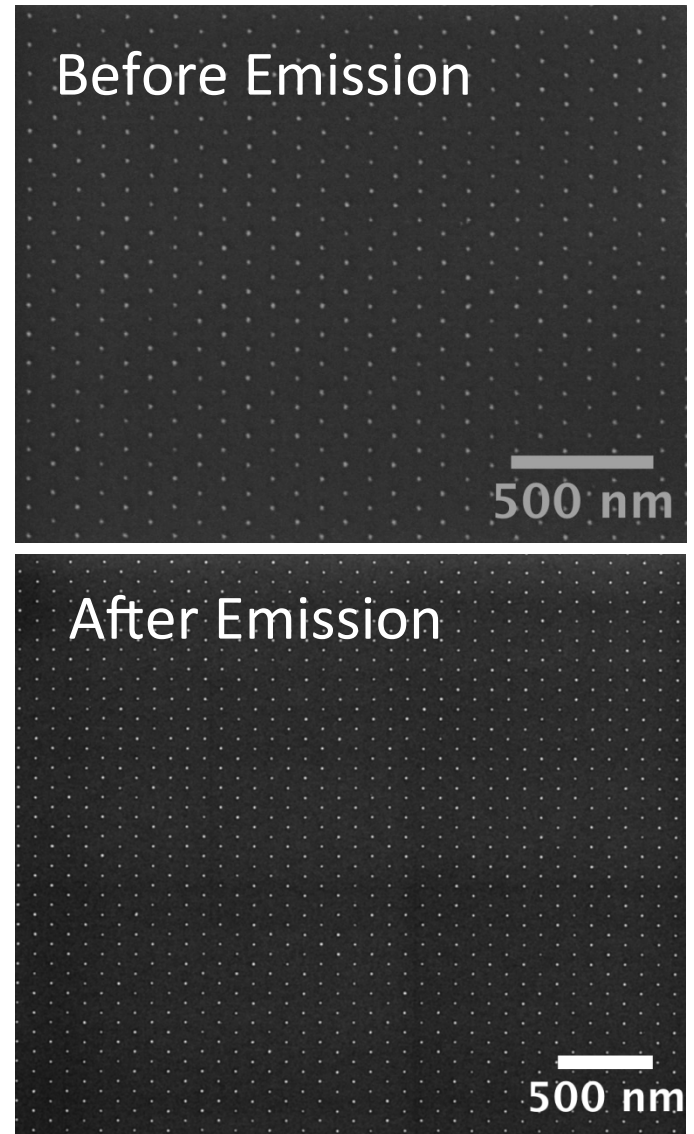
<sup>1</sup>Krolikowski, W. F.; Spicer, W. E. *Phys. Rev. B*, **1970**, *1*, 478

<sup>2</sup>Bormann, R.; Gulde, M.; Weismann, A.; Yalunin, S.V.; Ropers, C. *Phys. Rev. Lett.*, **2010**, *105*, 147601



# Laser Ablation?

- SEM imaging before and after emission confirms absence of extensive laser ablation
- Further high-resolution imaging required to investigate
  - Surface melting
  - Au surface desorption
  - Electromigration



# Future Work

---

- Comprehensive characterization of electron emission from various cathode materials
  - Total current yield
  - Emittance from single emitters and arrays thereof
  - Charge uniformity across the emitter array
- Selection of an optimal material and structure to generate coherent x-rays in the range 8-80 keV

# Acknowledgements

---

- James Daley, Vitor Manfrinato, Corey Fucetola and Tim Savas at the Nanostructures Laboratory, MIT

